Docket No.: 60188-725 PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277

Mitsuyasu OHTA, et al. : Confirmation Number:

Serial No.: Continuation of Appl. No.

09/381,377 : Group Art Unit:

Filed: January 06, 2004 : Examiner:

For: FUNCTIONAL BLOCK FOR INTEGRATED CIRCUIT, SEMICONDUCTOR

INTEGRATED CIRCUIT, METHOD FOR TESTING SEMICONDUCTOR

INTEGRATED CIRCUT, AND METHOD FOR DESIGNING SEMICONDUCTOR

INTEGRATED CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Serial No.: Continuation of Appl. No.

The references were cited by or submitted to the U.S. Patent and Trademark Office in parent application Serial No. <u>09/381,377</u>, filed <u>September 20, 1999</u>, which is relied upon for an earlier filing date under 35 USC 120. Thus, copies of these references are not attached. <u>37 CFR 1.98(d)</u>.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

Michael E. Fogarty

Registration No. 36,139

600 13th Street, N.W. Washington, DC 20005-3096 (202) 756-8000 MEF:prg

Facsimile: (202) 756-8087

Date: January 6, 2004

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					APPLICANT Mitsuyasu OHTA, et al.					
(PTO-1449)					FILING DATE January 06, 2004	GROUP				
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INITIALS	CITE NO.	Country Codes -Number 4 -Kind Codes (if known)		MM-DD-YYYY		Where Relevant Figures Appear				
		<u> </u>						Yes	No No	
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EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
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	L	<u> </u>								
EXAMINER					DATE CONSIDERED					

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.